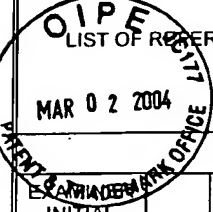


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 220471US2S		SERIAL NO. 10/091,423	
				APPLICANT Yusuke KAWAGUCHI, et al.			
				FILING DATE March 7, 2002		GROUP 2826	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
P ₆	AA	4,941,026	07/10/90	TEMPLE			
P ₆	AB	5,637,898	06/10/97	BALIGA			
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	EP 0 238 749 A2	09/30/87	EUROPEAN			
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
P ₆	AW	BALIGA, B. J., "Critical Nature of Oxide/Interface Quality for SiC Power Devices", 9 th Biennial Conference on Insulating Films on Semiconductors, Villard De Lans, France, 7-10 June 1995, Microelectronic Engineering, June 1995, Elsevier Publishers B.V., Amsterdam, Netherlands, vol. 28, no. 1-4, pages 177-184.					
	AX						
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <i>Sum</i> <i>Ram</i> <i>bro</i>					Date Considered <i>02/24/05</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							